

# PRE-RELEASE VERSION (FDIS)



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**Instruments and software used for measurement in high-voltage and high-current tests –  
Part 3: Requirements for hardware for tests with alternating and direct voltages and currents**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INSTRUMENTS AND SOFTWARE USED FOR MEASUREMENT  
IN HIGH-VOLTAGE AND HIGH-CURRENT TESTS –**

**Part 3: Requirements for hardware for tests with alternating  
and direct voltages and currents**

FOREWORD

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International Standard IEC 61083-3 has been prepared by IEC technical committee 42: High-voltage and high-current test techniques.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
42/XX/FDIS	42/XX/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61083 series, published under the general title *Instruments and software used for measurement in high-voltage and high-current tests*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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## INTRODUCTION

The electric power industry requires standardized tools to provide confidence in testing results, and to prove equivalence between tests performed in different laboratories and test fields.

This part of IEC 61083 specifies requirements for the performance of digital recording instruments used for tests with alternating and direct voltages and currents.

The intention of this document is to provide recommendations on the digital recording instruments to be used in tests with alternating and direct voltages and currents.

Digital recording instruments are considered as black boxes (including hardware, firmware, and software). They are characterized for their intended application by physical calibration with the waveforms needed for that application.

This document does not apply to simple analogue or digital meters that do not have recording capability.

# INSTRUMENTS AND SOFTWARE USED FOR MEASUREMENT IN HIGH-VOLTAGE AND HIGH-CURRENT TESTS –

## Part 3: Requirements for hardware for tests with alternating and direct voltages and currents

### 1 Scope

This part of IEC 61083 is applicable to digital recording instruments used for measurements during tests with high alternating and direct voltages and currents. It specifies the measuring characteristics and calibrations required to meet the measuring uncertainties and procedures specified in the relevant IEC standards (e.g. IEC 60060-1, IEC 60060-2, IEC 60060-3, IEC 62475, IEC 61180).

This document is applicable to those digital recording instruments that will be designed and type tested according to this document.

This document

- defines performance requirements for digital recording instruments used during tests with alternating voltages and currents (AC) or direct voltages and currents (DC);
- specifies the necessary requirements for such instruments to ensure their suitability for use under the relevant standards;
- establishes the tests and procedures necessary to demonstrate their compliance;
- defines the terms related to digital recording instruments with recording function and access to raw data.

NOTE Examples of relevant alternating and direct voltages and currents to be measured are listed in Annex D.

This International Standard has the status of a horizontal standard in accordance with IEC Guide 108.

### 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60060-2, *High-voltage test techniques – Part 2: Measuring systems*

IEC 61180, *High-voltage test techniques for low-voltage equipment – Definitions, test and procedure requirements, test equipment*

IEC 62475, *High-current test techniques – Definitions and requirements for test currents and measuring systems*

ISO/IEC Guide 98-3:2008, *Uncertainty of measurement – Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)*